

Notice of References Cited	Application/Control No. 10/604,341	Applicant(s)/Patent Under Reexamination CHEN, YINAN	
	Examiner Jennifer M. Kennedy	Art Unit 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,498,061 B2	12-2002	Divakaruni et al.	438/243
	B	US-6,426,253 B1	07-2002	Tews et al.	438/243
	C	US-6,521,493 B1	02-2003	Alsmeier et al.	438/199
	D	US-6,518,118 B2	02-2003	Athavale et al.	438/243
	E	US-6,426,526 B1	07-2002	Divakaruni et al.	257/302
	F	US-6,323,106 B1	11-2001	Huang et al.	438/433
	G	US-6,541,350 B2	04-2003	Chen, Wei-Wen	438/424
	H	US-6,649,928 B2	11-2003	Dennison, Charles	257/4
	I	US-2002/0121704 A1	09-2002	Lowrey et al.	257/774
	J	US-6,573,137 B1	06-2003	Divakaruni et al.	438/248
	K	US-6,593,612 B2	07-2003	Gruening et al.	257/301
	L	US-5,240,875	08-1993	Tsou, Len-Yuan	438/696
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04061346 A	02-1992	Japan	MINATO, TADAHARU	H01L 21/331
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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